

# AOT2142L/AOTF2142L

40V N-Channel MOSFET

#### **General Description**

Trench Power MV MOSFET technology

• Low R<sub>DS(ON)</sub>

Low Gate Charge

Optimized for fast-switching applications

### **Product Summary**

 $\begin{array}{lll} V_{DS} & 40V \\ I_{D} \; (at \, V_{GS} \! = \! 10V) & 120A \, / \, 112A \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 10V) & < 1.9 m\Omega \\ R_{DS(ON)} \; (at \, V_{GS} \! = \! 4.5V) & < 2.5 m\Omega \end{array}$ 

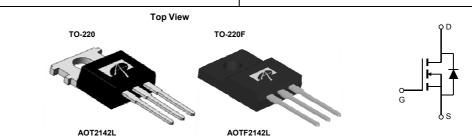
100% UIS Tested 100% Rg Tested



## **Applications**

Synchronous Rectification in DC/DC and AC/DC Converters

Isolated DC/DC Converters in Telecom and Industrial



Orderable Part Number	Package Type	Form	Minimum Order Quantity		
AOT2142L	TO-220	Tube	1000		
AOTF2142L	TO-220F	Tube	1000		

#### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted AOTF2142L(Max) Units Parameter Symbol AOT2142L(Max) Drain-Source Voltage 40 ٧ $V_{DS}$ Gate-Source Voltage V $V_{GS}$ ±20 T<sub>C</sub>=25°C 120 <sup>G</sup> 112 Continuous Drain T<sub>C</sub>=100°C 120 <sup>G</sup> 78 Current Α Pulsed Drain Current 600 $I_{DM}$ T<sub>A</sub>=25°C 50 Continuous Drain $I_{DSM}$ Α T<sub>A</sub>=70°C 40 Current Avalanche Current 60 Α $I_{AS}$ Avalanche energy L=0.3mH $\mathsf{E}_{\mathtt{AS}}$ 540 mJ V<sub>DS</sub> Spike 10µs $V_{\text{SPIKE}}$ 48 T<sub>C</sub>=25°C 312 $P_D$ W Power Dissipation B T<sub>C</sub>=100°C 156 20 T<sub>A</sub>=25°C 8.3 $P_{DSM}$ W T<sub>A</sub>=70°C Power Dissipation A 5.3 °C Junction and Storage Temperature Range -55 to 175 $T_J$ , $T_{STG}$

Thermal Characteristics									
Parameter		Symbol	AOT2142L(Max) AOTF2142L(Max)		Units				
Maximum Junction-to-Ambient A	t ≤ 10s	D	15	15	°C/W				
Maximum Junction-to-Ambient AD	Steady-State	− R <sub>θJA</sub>	60	60	°C/W				
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	0.48	3.6	°C/W				



## Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Parameter Conditions		Min	Тур	Max	Units
STATIC F	PARAMETERS						
$BV_{DSS}$	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V		40			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V				1	μA
	Zelo Gate Voltage Diaili Cullent		T <sub>J</sub> =55°C			5	μΛ
$I_{GSS}$	Gate-Body leakage current	$V_{DS}$ =0V, $V_{GS}$ =±20V	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS,}I_{D}=250\mu A$		1.3	1.8	2.3	V
	Static Drain-Source On-Resistance	$V_{GS}$ =10V, $I_D$ =20A			1.55	1.9	mΩ
R <sub>DS(ON)</sub>			T <sub>J</sub> =125°C		2.25	2.8	
		$V_{GS}$ =4.5V, $I_D$ =20A			1.95	2.5	mΩ
<b>g</b> FS	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A			100		S
$V_{SD}$	Diode Forward Voltage	I <sub>S</sub> =1A,V <sub>GS</sub> =0V			0.66	1	V
Is	Maximum Body-Diode Continuous Current G(AOT2142L)					120	Α
Is	Maximum Body-Diode Continuous Current (AOTF2142L)					50	Α
DYNAMIC	PARAMETERS						
C <sub>iss</sub>	Input Capacitance				8320		pF
Coss	Output Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =20V, f=1MHz			1438		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				85		pF
$R_g$	Gate resistance	f=1MHz		0.5	1.15	1.8	Ω
SWITCHI	NG PARAMETERS						
Q <sub>g</sub> (10V)	Total Gate Charge				100		nC
Q <sub>g</sub> (4.5V)	Total Gate Charge	-V <sub>GS</sub> =10V, V <sub>DS</sub> =20V, I <sub>D</sub> =20A			45		nC
$Q_{gs}$	Gate Source Charge				25		nC
$Q_{gd}$	Gate Drain Charge				7		nC
t <sub>D(on)</sub>	Turn-On DelayTime	$V_{GS}$ =10V, $V_{DS}$ =20V, $R_{L}$ =1.0 $\Omega$ , $R_{GEN}$ =3 $\Omega$			19		ns
t <sub>r</sub>	Turn-On Rise Time				7		ns
$t_{D(off)}$	Turn-Off DelayTime				69		ns
t <sub>f</sub>	Turn-Off Fall Time				10		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, dI/dt=400A/μs			26		ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	e I <sub>F</sub> =20A, dI/dt=400A/μ	s		83		nC

A. The value of  $R_{\text{BJA}}$  is measured with the device mounted on  $1\text{in}^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25° C. The Power dissipation  $P_{\text{DSM}}$  is based on  $R_{\text{BJA}}$  t≤ 10s and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

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B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}$ =175° C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(MAX)}$ =175° C.

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

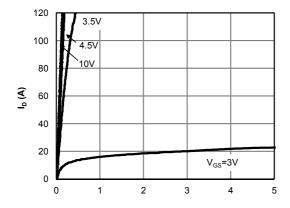
E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(MAX)}=175^{\circ}$  C. The SOA curve provides a single pulse rating.

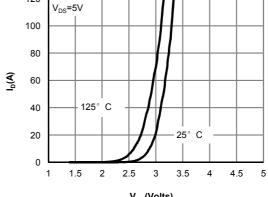
G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in FR-4 board with 2oz. Copper, in a still air environment with  $T_A$ =25° C.



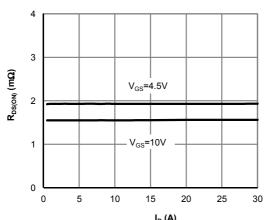


 $V_{\rm DS}$  (Volts) Figure 1: On-Region Characteristics (Note E)

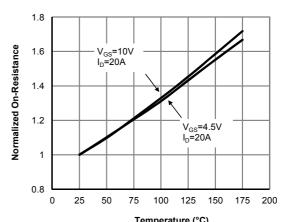


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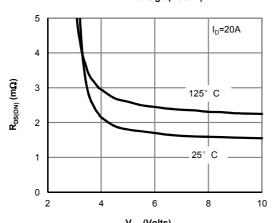
V<sub>GS</sub>(Volts) Figure 2: Transfer Characteristics (Note E)



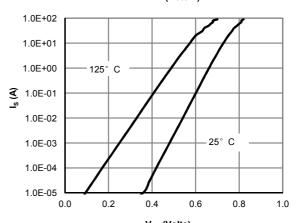
 $\label{eq:local_local} \textbf{I}_{\text{D}}\left(\textbf{A}\right)$  Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)



Temperature (°C)
Figure 4: On-Resistance vs. Junction Temperature
(Note E)

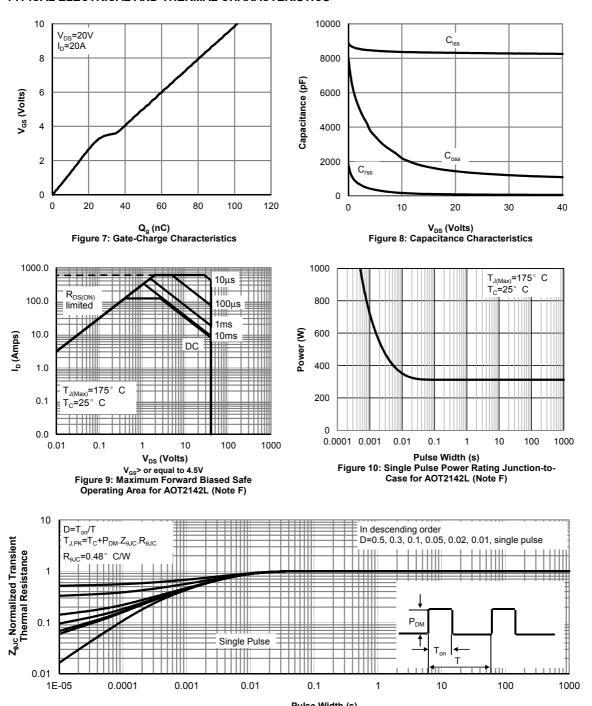


V<sub>GS</sub> (Volts)
Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)



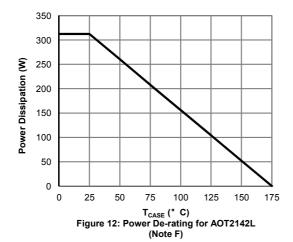
V<sub>SD</sub> (Volts) Figure 6: Body-Diode Characteristics (Note E)

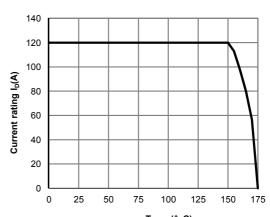




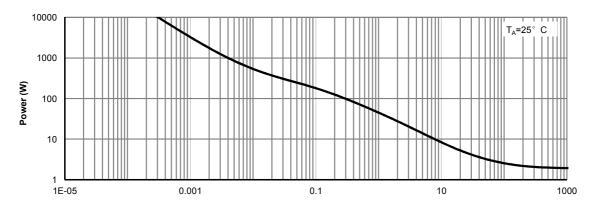
Pulse Width (s)
Figure 11: Normalized Maximum Transient Thermal Impedance for AOT2142L (Note F)



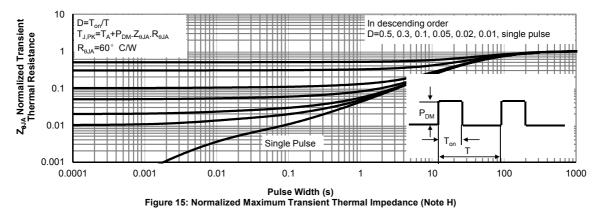




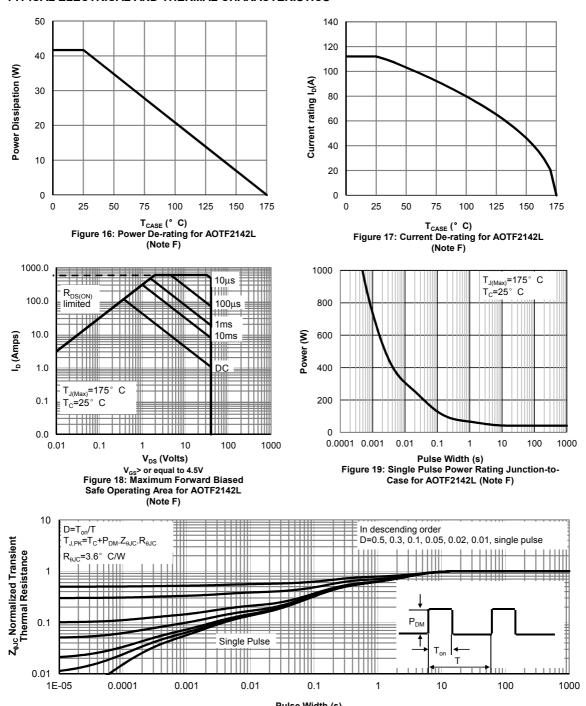
T<sub>CASE</sub> (° C)
Figure 13: Current De-rating for AOT2142L
(Note F)



Pulse Width (s) Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)



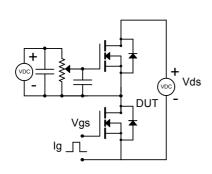


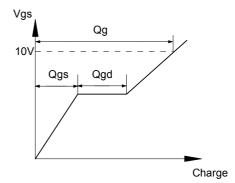


Pulse Width (s)
Figure 20: Normalized Maximum Transient Thermal Impedance for AOTF2142L (Note F)

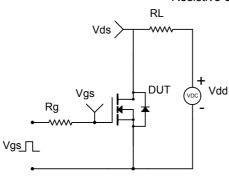


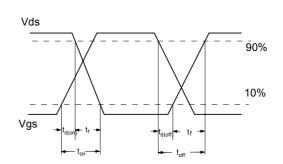
## Gate Charge Test Circuit & Waveform



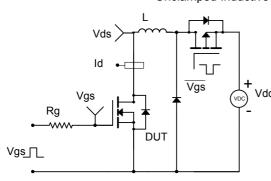


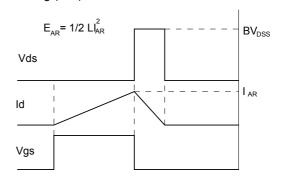
Resistive Switching Test Circuit & Waveforms





Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





## Diode Recovery Test Circuit & Waveforms

